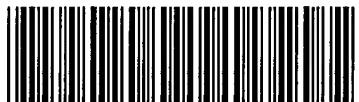


Search Notes**Application/Control No.**

10/549,615

Examiner

Linh V. Nguyen

Applicant(s)/Patent under Reexamination

HOSHINO ET AL.

Art Unit

2819

SEARCHED

Class	Subclass	Date	Examiner
375	340,341 335,265 207,267	1/13/2006	LN
370	252,335	1/13/2006	LN
370	270,331	1/13/2006	LN
714	702,755	1/13/2006	LN
341	50	1/13/2006	LN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East searched-see printout	1/13/2006	LN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner